Integrated Device Technology, Inc.
2975 Stender Way, Santa Clara, CA - 95054

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: **L-0501-03** DATE: 2/4/2005

Product Affected: Please see the attachment for the affected products

Date Effective: May 4, 2005

MEANS OF DISTINGUISHING CHANGED DEVICES:

- ☐ Product Mark
- ☐ Back Mark
- ■ Date Code — Prefix will change from "CD" & "CD4" to "Z"
- ☐ Other

Contact: Bimla Paul
Title: Quality Assurance Manager
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Attachment:: ■ Yes ☐ No

Samples: Available upon request

DESCRIPTION AND PURPOSE OF CHANGE:

- ☐ Die Technology
- ☐ Wafer Fabrication Process
- ☐ Assembly Process
- ☐ Equipment
- ☐ Material
- ☐ Testing
- ☐ Manufacturing Site
- ☐ Data Sheet
- ■ Other

Die revision changes from "CD" & "CD4" to "**Z**" on selected PLL Clock Buffers.
There is no change in die technology nor data sheet specification.
Please see the attachment for the affected products.

RELIABILITY/QUALIFICATION SUMMARY:

Please see the attachment for reliability data.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.
IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: ____________________ ☐ ***Approval for shipments prior to effective date.***

Name/Date: ____________________ E-Mail Address: ____________________

Title: ____________________ Phone# /Fax# : ____________________

CUSTOMER COMMENTS: ____________________

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: DATE:

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ATTACHMENT - PCN #: L-0501-03

PCN Type: Die Revision Change

Data Sheet Change: None

Detail of Change: Die revision changes from "CD" & "CD4" to "**Z**" on selected PLL Clock Buffers.
There is no change in die technology nor data sheet specification.
Please see below for the affected products.

Affected Part #
IDT2305-1DC
IDT2305-1DC8
IDT2305-1HDC
IDT2305-1HDC8
IDT2305-1DCI
IDT2305-1DCI8
IDT2305-1HDCI
IDT2305-1HDCI8
IDT2305-1DCG
IDT2305-1DCG8
IDT2305-1HDCG
IDT2305-1HDCG8
IDT2305-1DCGI
IDT2305-1DCGI8
IDT2305-1HDCGI
IDT2305-1HDCGI8
IDT2308-1DC
IDT2308-1DC8
IDT2308-1HDC
IDT2308-1HDC8
IDT2308-2DC
IDT2308-2DC8
IDT2308-2HDC
IDT2308-2HDC8
IDT2308-3DC
IDT2308-3DC8
IDT2308-4DC
IDT2308-4DC8
IDT2308-5HDC
IDT2308-5HDC8
IDT2308-1DCI
IDT2308-1DCI8
IDT2308-1HDCI

Affected Part #
IDT2308-1HDCI8
IDT2308-2DCI
IDT2308-2DCI8
IDT2308-2HDCI
IDT2308-2HDCI8
IDT2308-3DCI
IDT2308-3DCI8
IDT2308-4DCI
IDT2308-4DCI8
IDT2308-5HDCI
IDT2308-5HDCI8
IDT2308-1HDCG
IDT2308-1HDCG8
IDT2308-2DCG
IDT2308-2DCG8
IDT2308-2DCGI
IDT2308-2DCGI8
IDT2308-1HPG
IDT2308-1HPG8
IDT2308-2HPG
IDT2308-2HPG8
IDT2308-5HPG
IDT2308-5HPG8
IDT2308-1HPGI
IDT2308-1HPGI8
IDT2308-2HPGI
IDT2308-2HPGI8
IDT2308-5HPGI
IDT2308-5HPGI8
IDT2308-1HPGG
IDT2308-1HPGG8
IDT2308-1HPGGI
IDT2308-1HPGGI8

Affected Part #
IDT2309-1DC
IDT2309-1DC8
IDT2309-1HDC
IDT2309-1HDC8
IDT2309-1DCI
IDT2309-1DCI8
IDT2309-1HDCI
IDT2309-1HDCI8
IDT2309-1HDCG
IDT2309-1HDCG8
IDT2309-1HDCGI
IDT2309-1HDCGI8
IDT2309-1HPG
IDT2309-1HPG8
IDT2309-1HPGI
IDT2309-1HPGI8
IDT2309-1HPGG
IDT2309-1HPGG8
IDT2309-1HPGGI
IDT2309-1HPGGI8
IDT2309NZ-1HDC
IDT2309NZ-1HDC8
IDT2309NZ-1HDCI
IDT2309NZ-1HDCI8
IDT2309NZ-1HPG
IDT2309NZ-1HPG8
IDT2309NZ-1HPGI
IDT2309NZ-1HPGI8
IDT2309NZ-1HPGG
IDT2309NZ-1HPGG8
IDT2309NZ-1HPGGI
IDT2309NZ-1HPGGI8

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Qualification Plan: **QLG-04-17**

Following reliability tests were performed on IDT2308-1DC
The qualification results are as follow:

Test Description	Test Method	Required Sample/ # Fails	Test results
High Temperature Operating Life Test: Dynamic 1000 hrs @ 125°C	Mil-Std 883 Method 1005	77/0	77/0 @ 500 hrs; 1000 hrs is in progress
ESD Human Body Model	Mil-Std 883 Method 3015	3/0	3,000V
ESD Charged Device Model	JEDEC 22-101	3/0	1,000V
Latch-up	EIA/JESD STD-78	6/0	6/0